

Appln. No.: 09/832,933 Docket No.: BTAT.002US1
Title: Hot Carrier Circuit Reliability Simulation
Inventors: Wu et al.
Filing Date: 4/11/01 Atty. Tel: (415) 318-1160 Sheet 2 of 4

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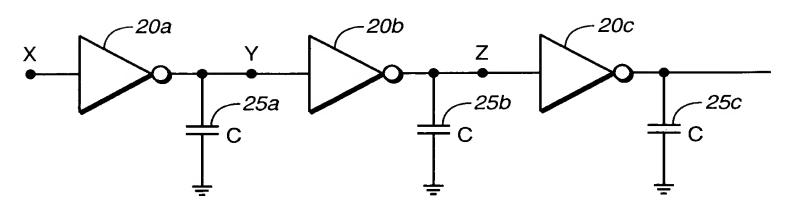


FIG.\_3

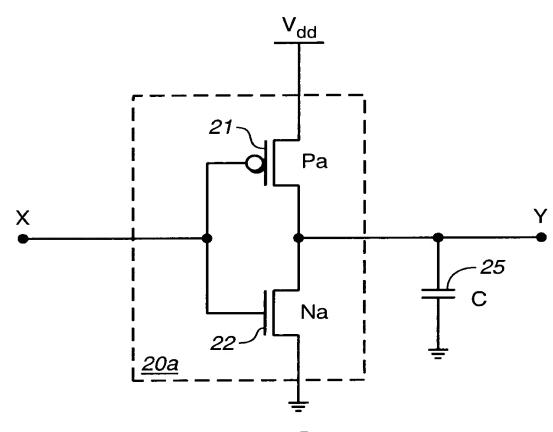
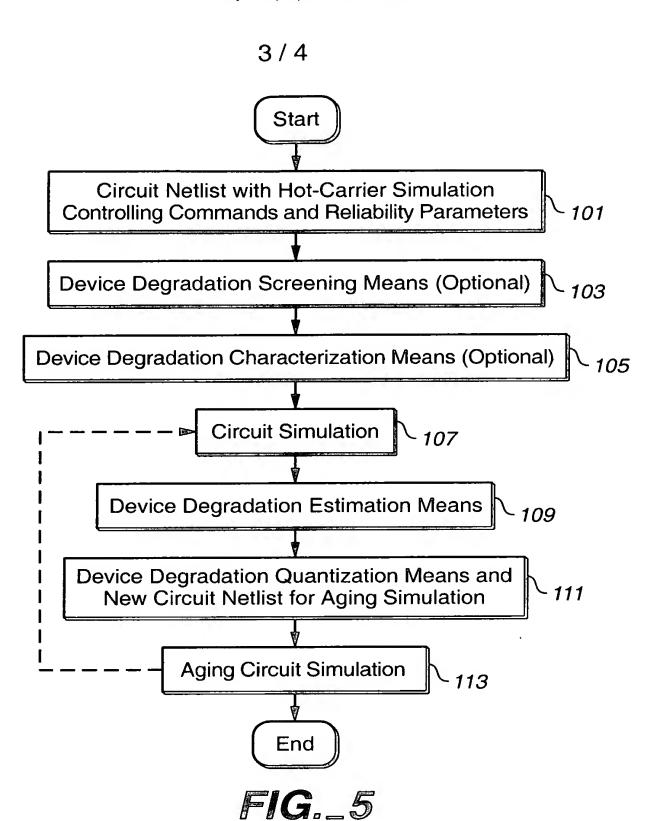


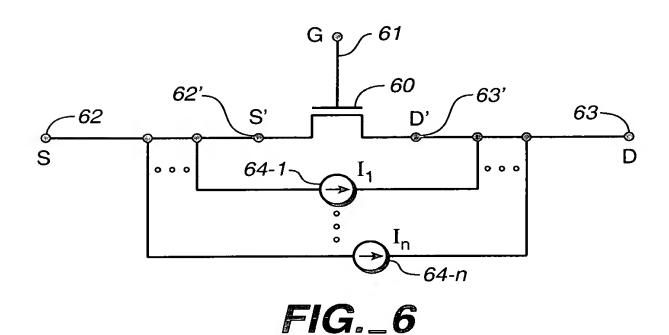
FIG.\_4

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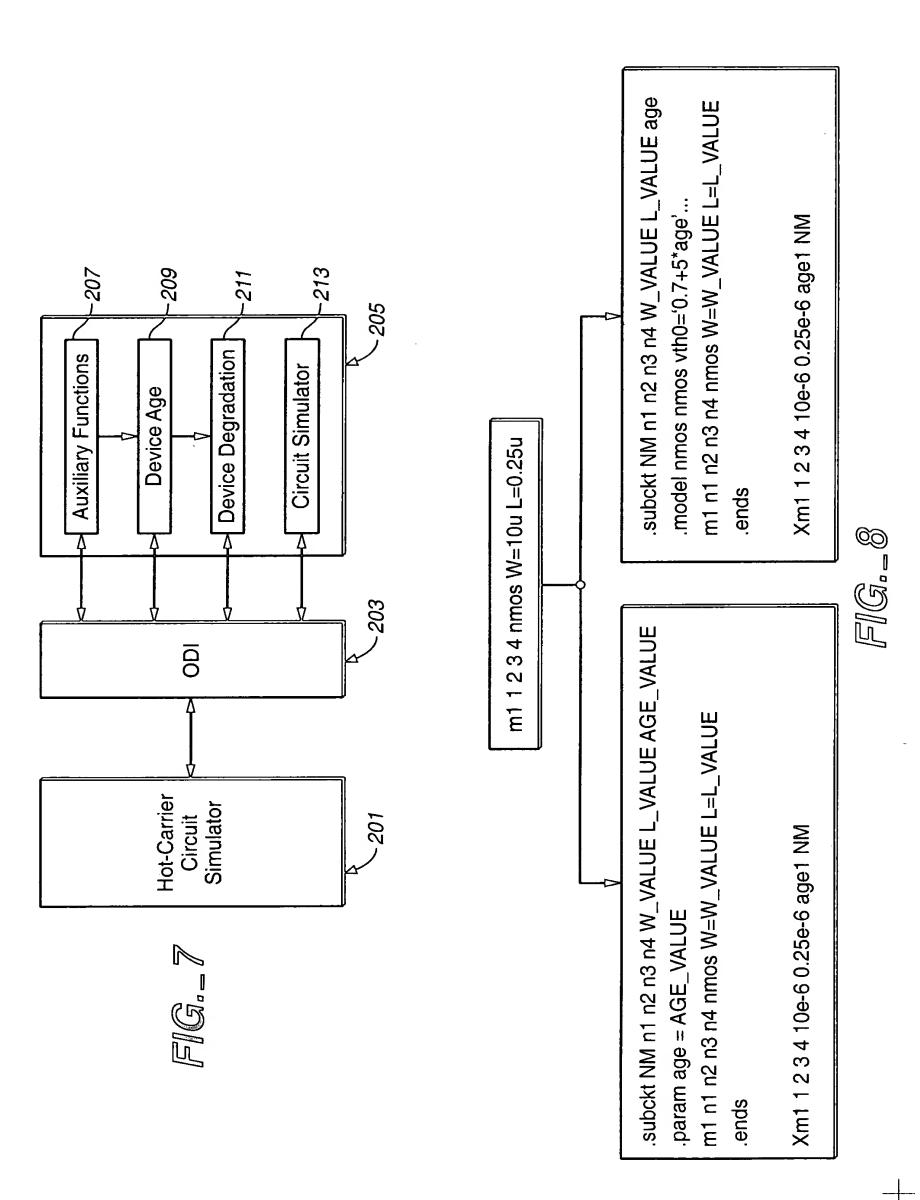




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